Deformation Behaviour and Cabling Degradation of Nb₃Sn Wires

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Introduction

- For accelerator applications, Nb₃Sn wires are assembled in the form of Rutherford cables, applying significant deformation to the wire, especially at the cable edges
- The resulting distortion of the wire cross-section before heat treatment can impact the I_c , RRR and stability:
 - Effects depend on the wire design, cabling and heat treatment parameters, and can vary between spools/billets
 - Important to assess the behaviour both for each type of wire and for individual billets
- As cable production consumes significant wire lengths and time, uniaxial rolling is commonly used as an (imperfect) proxy for initial acceptance tests
- Extensive data from systematic testing are available from the Bruker RRP[®] and PIT wire designs procured at scale for magnet production
- There is also a need to characterise a broader range of wire designs in the context of the High Field Magnets (HFM) programme:
 - Different RRP[®] layouts, especially at larger diameter
 - Wires developed in collaborations with other manufacturers: notably distributed tin (DT) wire from JASTEC and KAT
 - Ultimately, wires developed towards the challenging performance targets of ultimate Nb₃Sn dipole magnets, e.g. a non-Cu J_c of 1500 A/mm² (4.2 K 16 T)
- This presentation summarises the rolling and cabling behaviour of several wire types, combining rolling studies of individual spools with statistical analysis of rolling and cabling degradation over large-scale procurement



Rutherford Cable Deformation

- Strands at the centre of the cable width typically have a nominal thickness reduction ~11 %
 - Rolling studies typically performed for 10 % and/or 15 % uniaxial rolling reduction
- The real deformation, especially at the (thin) edge, is more severe and not uniaxial
 - All strands experience this periodically, at a transposition length typically much shorter than the lengths of samples used for I_c and RRR
- Stresses align along shear planes, but the resulting deformation of sub-elements depends on the wire type and its local orientation [1]
- Sub-element deformation affects performance via several mechanisms:
 - Sub-element shearing and merging
 - Changes in local barrier thickness and diffusion distances





Courtesy of Algirdas Baskys [1] *IEEE Trans Appl. Supercond.* **33** (5) 4801605, <u>10.1109/TASC.2023.3265910</u>





Previous Work

- The rolling and cabling degradation of RRP[®] and PIT wires has been extensively studied over many years, especially for wires of interest for HL-LHC and LARP
 - The key deformation characteristics were imaged, and their impact on superconducting performance directly observed, many years ago





Wire Types

- Three wire types of interest:
 - RRP[®] (Bruker OST) internal tin sub-elements in a distributed barrier configuration
 - PIT (Bruker EAS) powder-in-tube filaments, with an additional common diffusion barrier in the 'bundle-barrier' (HEP) variant ('PIT-BB')
 - Distributed tin (JASTEC, KAT) internal tin wire with alternating Nb and Sn(Ti) modules and a common external diffusion barrier
 - R&D wires developed in collaborations in the context of the High Field Magnets programme
- Each type has a distinct deformation behaviour and would be expected to show a different sensitivity of I_c and RRR to deformation
 - For RRP[®], different layouts/restacks can be compared
 - For RRP® and PIT, characterisation of large procured quantities permits statistical analysis









RRP[®] Wire Characteristics

	HL-I	LHC	HFM		
	11 T dipole	MQXF	ERMC-1	DEM-1.1	
Diameter (mm)	0.7	0.85	1.0	1.1	
Layout	108/	/127	162/169		
<i>d_s</i> (μm)	45	54	58	64	
Cu/non-Cu	1.15 ± 0.1	1.2 ± 0.1 0.9 ± 0.2		± 0.2	
Nb:Sn	3.6 (redu	uced Sn)	3.4 (standard Sn)		
Heat treatment	650 °C 50 h	665 °C 50 h	650 °C 50 h	665 °C 50 h	



RRP®: Statistics from Acceptance Tests

- For HL-LHC, 108/127 RRP[®] was procured in significantly quantities at 0.7 mm (for 11 T dipoles) and 0.85 mm (for MQXF) diameter
 - Acceptance tests included measurements of every spool
 - 15 % rolling data for all billets
- Similar testing, but with a lower overall quantity and sampling rate, applied to 162/169 RRP[®] wire procured for FCC/HFM
- The following slides include both:
 - Studies at different rolling reductions for individual spools
 - Statistical evaluation of the behaviour over all procured series spools
- In each case, data are presented only for the standard heat treatment





RRP[®] Rolling: Key Features

- Visually apparent that progressive rolling:
 - Increases subelement aspect ratios
 - Locally reduces diffusion barrier (and Nb filament pack) thickness
 - Shears or merges adjacent subelements
- These observations can be quantified by image analysis:
 - Performed for a set of adjacent samples from **one spool** reacted in a single heat treatment





RRP® 108/127: Aspect Ratio



- The average subelement aspect ratio increases, and the distribution of aspect ratios broadens, with increasing rolling reduction
 - Particularly sharp increase from 20 % to 30 % rolling, corresponding to more frequent shearing/merging of subelements
 - Similar observations for subelement area and perimeter





RRP[®] Rolling: After Reaction

- After reaction, the aspect ratio distribution remains similar but areas expand (due to the expected volumetric expansion of Nb \rightarrow Nb₃Sn)
- At 20 % and 30 % rolling, local instances of complete barrier reaction and/or breaks due to shearing become more prevalent, resulting in increased Sn loss to the matrix, and intermittent discontinuities and contacts in Nb₃Sn subelements





RRP[®]: Effect on *I_c* and RRR



- *I_c* and RRR both decrease progressively on rolling, on average, with a steeper gradient between 15 % and 20% rolling reduction
 - *I_c* significant spread at modest rolling reduction: average 'degradation' is *negative*, -0.6 %, for 15 % rolling
 - RRR less variable, with a significant degradation even for small rolling reductions: average 36 % for 15 % rolling





Comparison of RRP[®] Layouts

- For 15 % rolling, acceptance test statistics are available for a significant number of spools
- Relative to 108/127 at 0.85 mm, 162/169 at 1.1 mm shows (on average):
 - **Higher** I_c degradation –**1.5 %**, cf. -0.6 %
 - Lower RRR degradation 23 %, cf. 36 %





Comparison of RRP[®] and PIT (1)

- The behaviour is similar for all tested RRP[®] wires
- Differences between (say) 108/127 and 162/169 may also be partly due to differing diameter, Cu/non-Cu, Sn stoichiometry, or HT cycles
 - For the same restack, I_c degradation slightly higher for the larger-diameter wire
- **PIT** wires differ significantly in design (round filaments) and the nature of imperfections
- ... but the evolution of the aspect ratio distribution of PIT and RRP[®] wires on rolling is remarkably similar







Cumulative aspect ratio distribution for 0.85 mm wires: RRP[®] 108/127 subelements and PIT-BB 192 filaments



Comparison of RRP[®] and PIT (2)

- The performance impact of filament distortion for PIT BB does differ significantly
- Tin loss through locally fully-reacted or broken tubes:
 - Barely affects the measured RRR (due to the 'bundle barrier')
 - Significantly reduces *I_c*, as the reaction of the filament stops
- Consequently, PIT wire shows markedly higher average *I_c* degradation (mean 8.8 %) on 15 % rolling, and a much broader distribution



Comparison of I_c degradation distributions after 15 % rolling for RRP[®] 108/127 and PIT-BB wires



Comparison with Cables

- I_c degradation on cabling depends on the cable configuration
- Taking statistics for cables of the HL-LHC MQXF design, using 0.85 mm strand, the **mean** I_c degradation is:
 - RRP[®] 108/127: **2.8 %**
 - PIT BB: **11 %**
- ... in both cases, **significantly higher** than for 15 % rolling:
 - For RRP, for the individual spool test, this is comparable to a rolling reduction of **17.5** %
 - For PIT, the distribution of degradation values is too broad to compare with a single example
- RRR degradation is:
 - For RRP, 16.9 % on average approximately half that of 15 % rolled samples
 - Negligible for PIT due to the external barrier
 - Assessing degradation of RRR by rolling is conservative, as 15 % reduction is larger than experienced across the majority of the cable width
 - Local degradation at the cable edges should be separately measured *locally*



MQXF cable with 40 RRP[®] 108/127 strands)





Local RRR

- Typically, high purity (high RRR) Cu is used throughout the cross-section in manufacturing
- At the time of cabling, the wire is already heavily cold-worked from wire drawing
 - Little further change expected in Cu RRR or resistivity
 - Small differences across the cross-section may result from differences in starting Cu forms, grain sizes and wire processing routes etc.
- RRR is measured **after** heat treatment: variations are usually dominated by tin contamination
 - Longitudinally for an extracted strand, the deformation locally at the cable edge reduces RRR
 - In the cross-section RRR is often very high in regions protected by thick/intact diffusion barriers, but can be reduced strongly locally in interfilamentary regions



Local RRR Degradation at Edges

- Local measurement of RRR confirms the expected behaviour •
- Relative to the standard (for CERN) RRR measurement, RRR is: ٠
 - Higher at the cable centre
 - Lower at the edges, especially the thin edge
- Values below are averages for two extracted strand samples of MQXF cables (RRP[®] wire) •
- At present, samples may be bent for mounting in a sample holder optimised for straight ٠ samples: systematic measurement of local RRR will require a new design





holder



Local RRR Across Wire Cross-Sections (1)

- For wires with a common external barrier, etching the outer Cu allows the RRR to be measured for the central matrix only
 - For DT wires, this region is intentionally used for Sn transport, so it is **not** included in the Cu area for Cu/non-Cu
 - For PIT-BB, the barrier was added to retain acceptable RRR with a heat treatment achieving high I_c, so some RRR degradation of the matrix was anticipated, but internal Cu area was included in Cu/non-Cu
 - Further study is needed to assess the impact of RRR variations in the cross-section on stability, protection etc.



Local RRR Across Wire Cross-Sections (2)

- The RRR of the central Cu of PIT-BB is very low, and reduced further on rolling •
 - The RRR of the outer Cu alone is estimated to be very high, as for DT wires
- For a sample of wire with known low starting Cu RRR, the central Cu did not have a lower RRR after • heat treatment than typical wires: the overall RRR is dominated by the outer Cu
- For a wire produced with improved filament geometry, the RRR was significantly improved, with the • central region RRR (~140) potentially high enough to consider as part of the stabiliser

PIT-BB Type	Sample	Rolling	RRR	Etched RRR (central Cu)	Estimated RRR of outer Cu	
Series Wires	1	0 %	188	23.5	361	
		15 %	189	7.7	353	
	2	0 %	134	11.5	319	
		15 %	151	6.3	337	
Low Cu RRR	3	0 %	76.2	26.4	-	
Improved Geometry	4	0 %	250.1	139.8	-	RRR measurements courte Al Baskys and Joanna Kucz



Joanna Kuczynska

Distributed Tin Wires

• Two manufacturers, JASTEC and KAT, have developed 'distributed tin' wires:



• KAT's designs have also included a copper core protected by an additional diffusion barrier

Supplier	<i>d</i> (mm)	Cu/non-Cu	Nb/Sn modules	Mean piece length (m)
KAT	1.0	0.93	138 + 54	1430
JASTEC	1.1	1.08	138 + 73	150



Cabling Trials at CERN

- Short trial cables successfully produced using cable designs established for magnet R&D activities
 - Rolling and cabling study for KAT previously reported at ASC 2022

Wir	ſe	Cable					
Supplier	<i>d</i> (mm)	Layout	Strands	Key- stone	Width (mm)	Mid-thickness (mm)	Core
KAT	1.0	FalconD	40	0.5°	20.95	1.8	14×0.025 mm 316L
JASTEC	1.1	R2D2 HF	21	None	12.579	1.969	None
		$\frac{0000}{000}$			KAT (FalconD)	88885	JASTEC (R2D2 HF)



Cable Cross-Sections

- Optical micrographs show, as expected:
 - Uniform strand cross-sections in the middle of the cable width
 - Significant distortion of module geometry and barrier thinning in the most deformed edge location





JASTEC Rolling: Key Features

• As observed for previous DT wires, Sn regions deform and merge, whilst Nb modules are largely displaced intact





Relative displacement of Nb

modules: Sn core merging



Shearing at periphery of Nb

modules: barrier thinning

20 %





Barrier breakage, extended Nb module shearing



28 September 2023

JASTEC Rolling: Aspect Ratios

- Aspect ratios do not show large increases, or form bands relative to the rolling direction:
 - Unlike RRP[®] or PIT see 3-MO-CS2-06S this afternoon
- Large variation in Nb modules between longitudinal positions, as broad Sn regions can open up locally





JASTEC: Reacted Strands

- After heat treatment and the Nb \rightarrow Nb₃Sn volume expansion, the separation of modules is locally small
 - Difficult to be certain if modules are in contact: colour maps below show **area**, but can be considered to highlight potential clusters of different numbers of modules in contact
 - As expected, the most distorted position at the cable edge exhibits larger clusters of modules potentially in contact → potential increase in *d*_{eff} and/or stability impact
- Considering only well-separated modules, the distribution of aspect ratios remains comparable to unreacted samples





KAT: Reacted Strands

- For KAT reacted strands, observations for subelement shape are similar to JASTEC
- In addition:
 - The area distribution plots highlight 6 clusters of Nb₃Sn regions in close proximity after reaction, which could contribute to increase d_{eff}
 - For larger rolling reductions, the internal diffusion barrier is severely deformed
 - The internal Cu volume is small, and not critical to Cu/non-Cu, but it may influence the deformation of neighbouring modules
 - Unreacted Nb is evident in the centre of some Nb modules, indicating the potential for increase I_c if tin supply can be improved by design or heat treatment







RRR

- The RRR of JASTEC and KAT rolled samples and extracted strands is extremely high due to the largely intact external diffusion barrier
 - RRR degradation reached ~50 % at 30 % rolling reduction for both JASTEC and KAT wire
 - RRR degradation appears a little higher at small rolling reductions for JASTEC, but few samples tested





Critical Current and Stability (1)

- For both the present DT wires, samples have frequently quenched in I_c testing at 12–15 T: difficult to obtain robust statistics for $I_c(B)$ performance
- Self-field instability would be expected to be challenging for these large diameter (1.0 and 1.1 mm), high J_c designs
 - Increased d_{eff} locally, e.g. at contact between subelements, may also contribute to magnetisation instability
- To evaluate the behaviour, multiple V–I transport measurements have been performed at both 4.3 K and 1.9 K:
 - Multiple measurements at each test field, starting at 15 T and proceeding downwards in small steps
 - Samples tested in pairs of different deformation state (rolled, extracted)



Critical Current and Stability (2)

- For the JASTEC wire:
 - A strand **extracted** from the cable appears to quench close to the onset of the I_c transition at:
 - 1.9 K: 12 T and above
 - 4.3 K: ~8 T and above in most cases
 - Extracted strand quench current curves at 1.9 K and 4.3 K intersect at ~ 8 T
 - For the **virgin** (round) wire:
 - At 4.3 K, values appear to be stability limited below ~13.5 T
 - Subsequent quench currents at 4.3 K, and all values at 1.9 K, are anomalously low compared to the extracted strand
 - Additional samples currently in testing





Critical Current and Stability (3)

- Comparing the JASTEC extracted strand and KAT samples, performance is less severely stability limited at low field for the JASTEC wire
 - This could potentially be addressed by heat treatment optimisation as well as design changes
 - Further tests are in progress





Future Prospects: Hf, Internal Oxidation

- A significant increase in J_{c} (relative to the RRP[®] baseline) probably requires new approaches:
 - Hf alloying was proposed to cause Nb₂Sn grain refinement by suppressing Nb alloy recrystallisation (NHFML, FSU, US)
 - S. Balachandran et al., Supercond. Sci. Technol. 32 044006 (2019)
 - Internal oxidation of Zr or Hf in Nb alloys forms oxide precipitates, acting as pinning centres and refining Nb₂Sn grain • sizes
 - X. Xu et al., Appl. Phys. Lett. 104 (8) 082602 (2014)
- Internal oxidation has been implemented in both PIT and internal tin wire types
 - The hardening behaviour of Hf-alloyed Nb-Ta poses some challenges in wire drawing, and potentially also in subsequent • cabling
- PIT wires produced at Hyper Tech (in collaboration with Fermilab and OSU) have shown excellent J_{α} but:
 - There is currently limited validation of stability and cabling behaviour
 - Many of the same optimisation challenges may apply as for conventional Bruker PIT wires
- Rod-in-tube wires are under development at UNIGE in collaboration with CERN
 - A similar J_c enhancement has been observed in model samples, and wire development in progress
 - An oxide powder is needed as an oxygen source: its configuration will also affect drawing and cabling behaviour





SEM cross-sections of reacted Hyper Tech Hfand Zr- alloyed internal oxidation PIT wires

X. Xu et al., Supercond. Sci. Technol. 36 035012 (2023)



320

300 (100 280 AH 240

ຕ<u>ີ</u> 220

180

160 140 듕

80

60

40

₹ 200

Har 120 100

G. Bovone et al., Supercond. Sci. Technol. 36 095018 (2023)



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10g load-

Nb4Ta1Hf(Commercial ATI)

True Strain, E, In (A₀/A)

S. Balachandran et al.,

https://dx.doi.org/10.2139/ssrn.4303410

Summary (1)

- The different deformation characteristics of RRP[®], PIT (BB) and DT wires have been assessed by electron microscopy, image analysis, and I_c and RRR measurement
 - RRP[®] and PIT wires show a similar evolution of subelement/filament aspect ratio, but the latter is more susceptible to *I_c* degradation
 - For DT wires, the deformation is mostly accommodated by displacement of Nb modules and deformation of Sn modules
 - I_c degradation is significantly higher (but still acceptably low, <5 %) for RRP[®] 162/169 (1.1 mm) than 108/127 (0.85 mm)
- 15 % rolled samples underestimate cabling degradation of I_c (17.5 % rolling may be more representative), but conservatively overestimate RRR degradation (as severe degradation is localised to the edges)
 - Work is in progress to evaluate RRR locally at the cable edge
 - Modelling of the strand deformation during rolling and cabling is planned



Summary (2)

- Distributed tin wires with comparable subelement size produced by JASTEC and KAT have been successfully cabled
- Deformation behaviour is broadly similar for both: Nb modules tend to move before they deform, with little increase in aspect ratio
 - RRR degradation on rolling and cabling is low, from a high baseline
 - There is little indication of I_c degradation on rolling or cabling, but data are limited due to stability issues
- For JASTEC strand extracted from a cable, quench currents at 1.9 K appear close to I_c , but results for the virgin strand were inconsistent
 - Tests of additional samples are in progress
- There are promising indications for the potential of distributed tin wires, and that further heat treatment optimisation would be beneficial
- Future trends in wire development, and the sensitivity of deformation behaviour to exact wire design and heat treatment, demonstrate the need for further study.



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 - For internal oxidation R&D: UNIGE
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